

Notice of References Cited	Application/Control No. 10/047,717	Applicant(s)/Patent Under Reexamination KNAPP, RICHARD J.	
	Examiner Tan Dean D. Nguyen	Art Unit 3629	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,043,894	03-2000	Van Aken et al.	356/425
*	B	US-5,737,518	04-1998	Grover et al.	714/38
*	C	US-5,771,354	06-1998	Crawford, Christopher M.	709/229
*	D	US-5,513,300	04-1996	Shibazaki, Hiroshi	358/1.13
*	E	US-7,012,617	03-2006	Luo et al.	345/593
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
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	X	

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